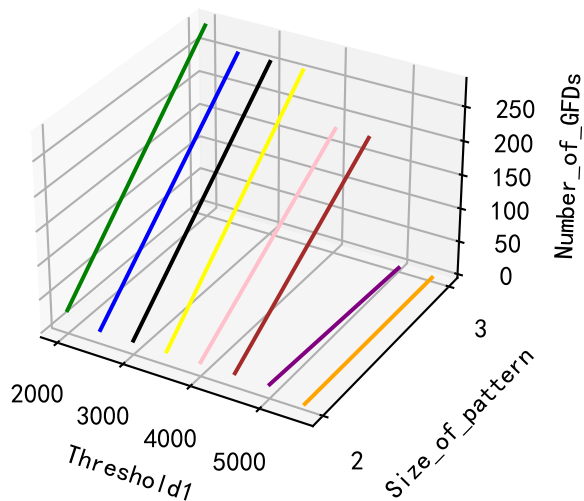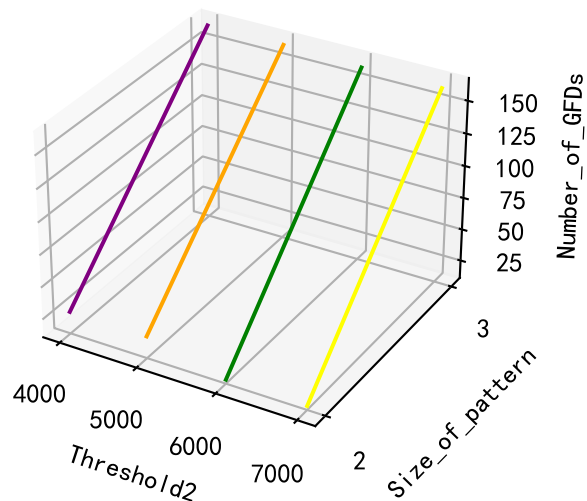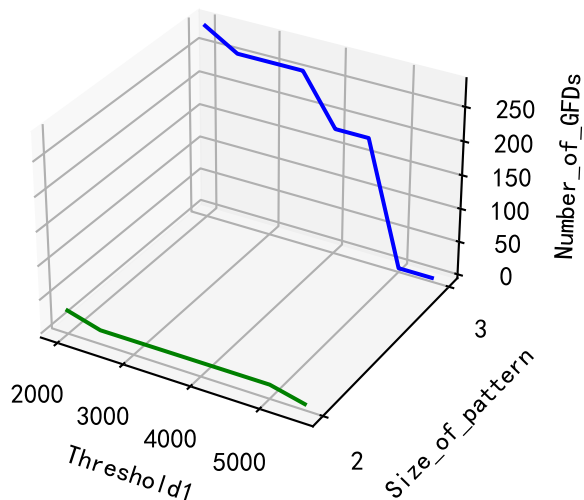(a) Exploring pattern size effect, new method

(b) Exploring pattern size effect, Fan method

(c) Exploring threshold effect, new method

(d) Exploring threshold effect, Fan method